

Erratum to: Anomalous Change of Transport Characteristics of Graphite Planar-Type Micro-structures Fabricated by Focused Ion Beam

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In the Experiment Details section (page No. 1194) the 3rd paragraph in which the mentioned stack height $H = 200$ nm should be read as $H = 300$ nm.

Similarly in Fig. 2 caption, $H = 200$ nm should be read as $H = 300$ nm. Also in the inset of Fig. 2(c), the denoted stack height 200 nm should be read as 300 nm.

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